

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination BEDELL ET AL.	
		Examiner Tianjie Chen	Art Unit 2652	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0191349 A1	12-2002	Hsu et al.	360/317
	B	US-6,570,739 B2	05-2003	Hsiao et al.	360/123
	C	US-2004/0165317 A1	08-2004	Westwood, John David	360/317
	D	US-2003/0218835 A1	11-2003	Hsiao et al.	360/317
	E	US-2002/0191350 A1	12-2002	Emilio Santini, Hugo Alberto	360/317
	F	US-6,859,997	03-2005	Tong et al.	29/603.13
	G	US-6,477,765	11-2002	Herrera, Steven Charles	29/603.14
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 03283104 A	12-1991	Japan	IMAOKA, HIROFUMI	-----
	O	JP 11120509 A	04-1999	Japan	ISE et al.	-----
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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